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5 526-1707

(74)  
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(54)

DUT (socket) (tester) , DUT  
가 , DUT(Device Under Test)

4

1 (Device Under Test, 'DUT')가

2 .

3 (test site) DUT .

4 (flow chart) .

5 .

6 (data sheet) .

7 DUT 가 ( block diagram) .

, DUT

, 가

(DRAM) (through put) 가

가 , 가 ,

, 32, 64 , 128

가

1 DUT가 .

1 (1000) (1100) (1000) (1200) (1000) (1100)가 ,

erator), (wave formatter), , DC(Direct Current) , (pattern gen  
(programmable power supply) DUT , (1000) (handler,  
2 2000) (2100) (2300)가 가 DUT (2100) (loading)

2

2 (2000) (2200) (2000) DUT DUT

(2400)가 (2100) (2300)가 가 DUT DUT  
(2500)가 (1000) (2700)

(2600) DUT가 , (2100) ,  
 가  
 (2100) DUT DUT (1000)  
 (2800)  
 , (2000) (1000) (2700) (2800)  
 , DUT (2100) DUT , (100  
 0) , (1000) DUT , DUT  
 3 (test site) DUT  
 3 , 가 , DUT (2110) (2102)  
 (2104) , 가 DUT (2104)  
 , 가  
 , 가  
 DUT DUT  
 DUT 가  
 , 가  
 , 2002-077598 (2002 10 12 ) ' DUT  
 , DUT (off) , 가 DUT  
 ,  
 DUT (socket)  
 , (handler  
 )가 DUT (DUT) (loading) DUT  
 DUT DUT  
 DUT DUT  
 , DUT DUT  
 가 , DUT DUT  
 , DUT , 가  
 , DUT , 가  
 , (continuity test results), (leakage test results) (timing test re  
 sults) ,  
 , DUT  
 , 가

가 가 가 가

DUT 가

가 DRAM

가 가

4 (flow chart)

4 가 (setup) DUT가

DUT (S100) DUT DRAM DUT

(S110) DUT DUT (S120) (S130)

가 가

/ (pass/fail) 가

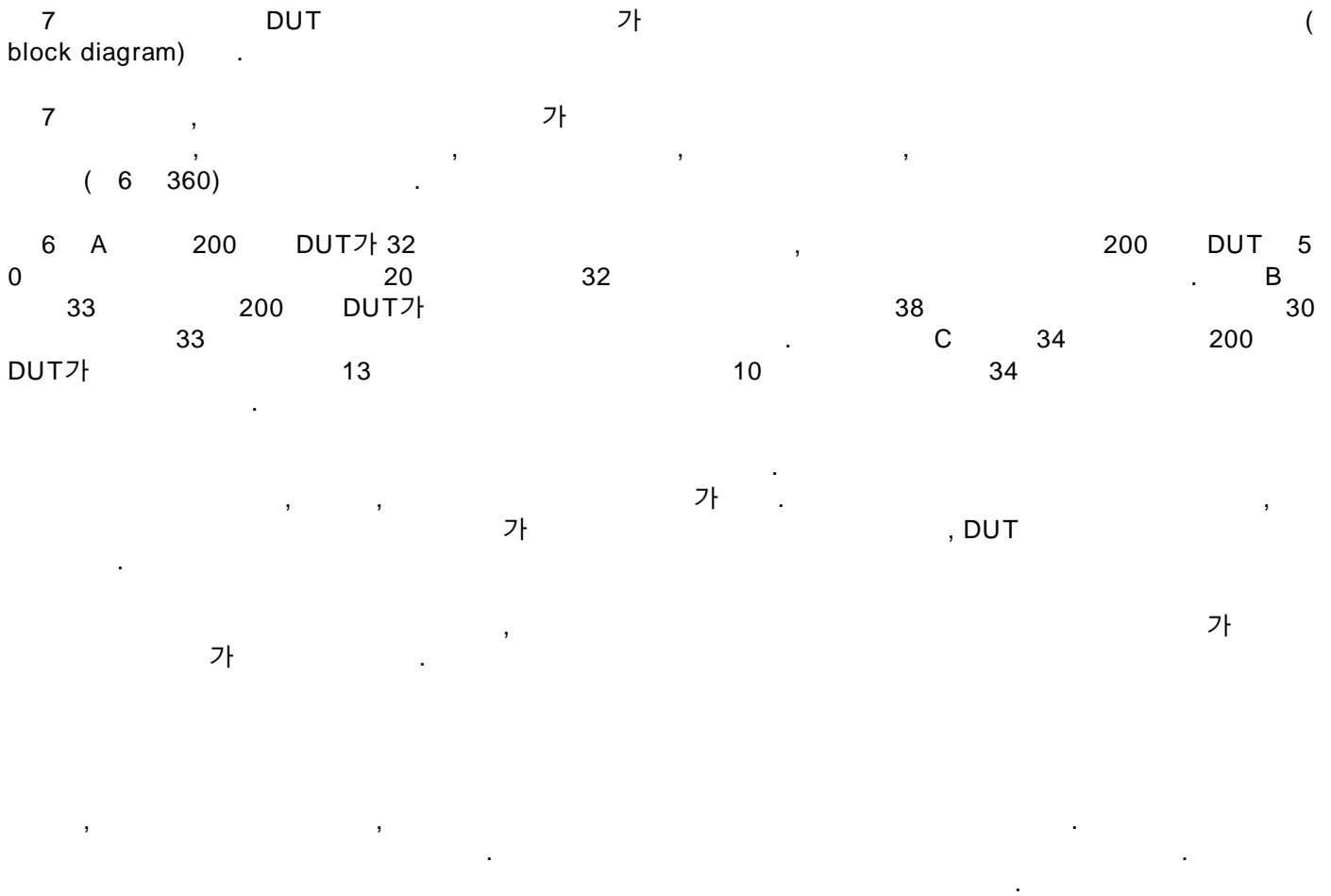
(open)/ (short)

(critical limit) /

/ 가 DUT (S140)

DUT 가 (S150)

가 , DUT DUT  
 , DUT .  
 7 가 (160) 6  
 (S170)  
 5  
 5 , (100) (open) (100) DUT가 DU  
 T (100) (100) DUT (short)  
 (100)  
 DUT (lot unit)  
 가 DUT 가 , 64 DUT , 64 DUT , 1  
 (100) 가 63 , 64 DUT , 1  
 (lot) 가 , 64 DUT DUT가 , 1  
 DC(Direct Current) test(110),  
 DUT (pin) 가 , 가  
 DUT DUT  
 DUT 가 DUT  
 DUT 가 (degradation)  
 (120) DUT,  
 (cell) DUT , 가  
 DUT  
 (AC test, 130) (130)  
 ) DUT (pulse) 가  
 DUT (130) 가  
 DUT 가 (degrad  
 ation)  
 6 (data sheet)  
 6 , 1 , 200  
 , socket No(210, 310) DUT  
 가 test item(220, 320)  
 가 DUT 가 . Pass  
 (240, 340) Fail(250, 350) DUT , DUT 가 . refere  
 nce data(260, 360) 가



(57)

1. (handler)가 DUT (DUT) (lo

ading) ;

DUT ;

DUT ;

DUT

DUT DUT ;

DUT ;

DUT 가 ;

DUT

2.

1 ,

1 3. ,

1 4. ,

DUT DUT가 가

1 5. ,

(DUT)

5 6. ,

(DRAM)

1 7. ,

(continuity test results)

1 8. ,

(leakage test results)

1 9. ,

(timing test results)

1 10. ,

가 DUT

1 11. ,

1 12. ,

,  
DUT 가  
.

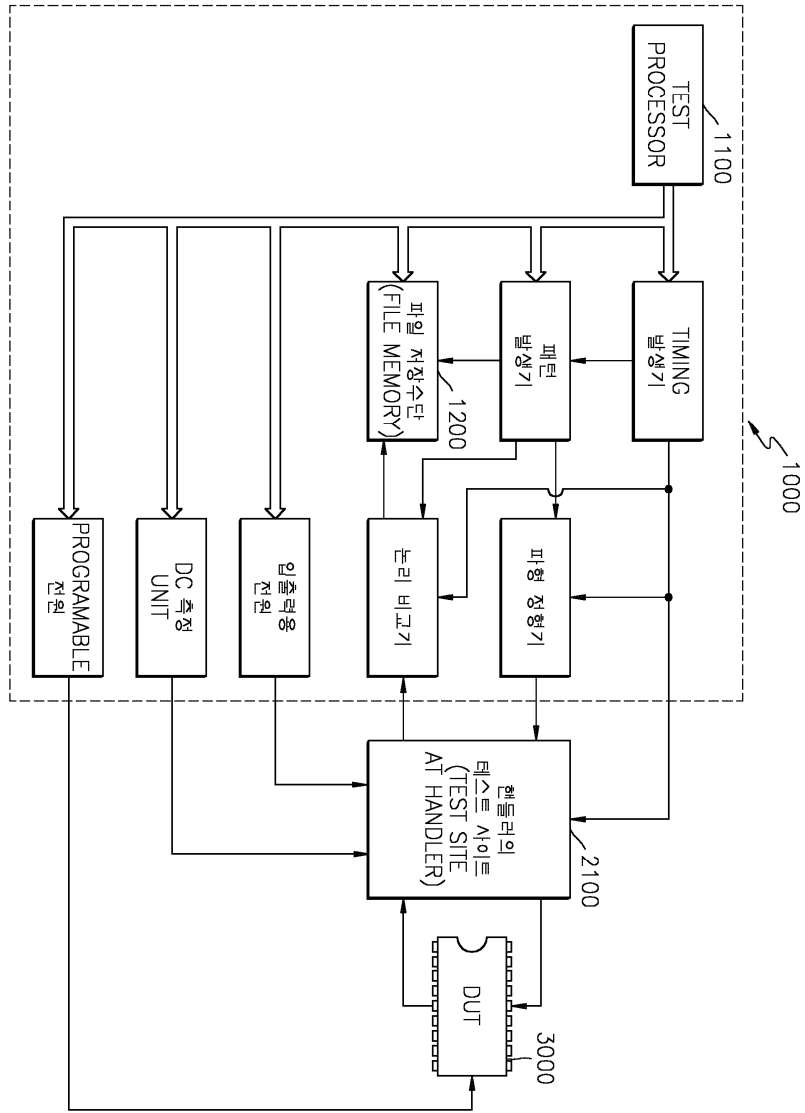
1 13. ,

1 14. ,

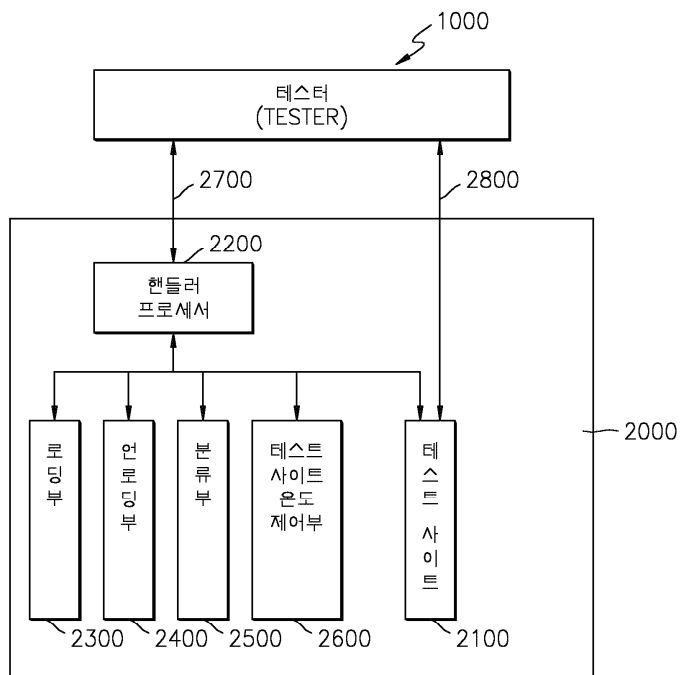
1 15. ,



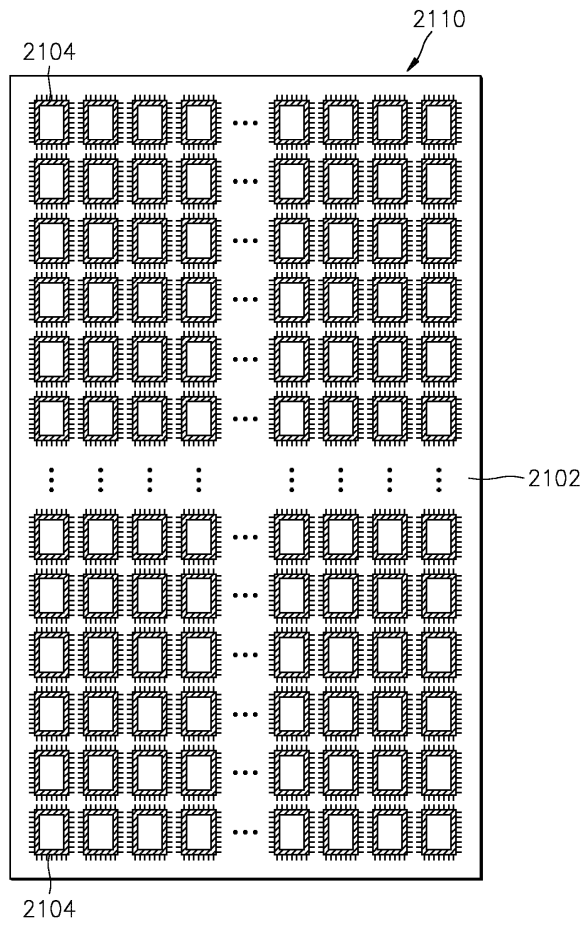
1



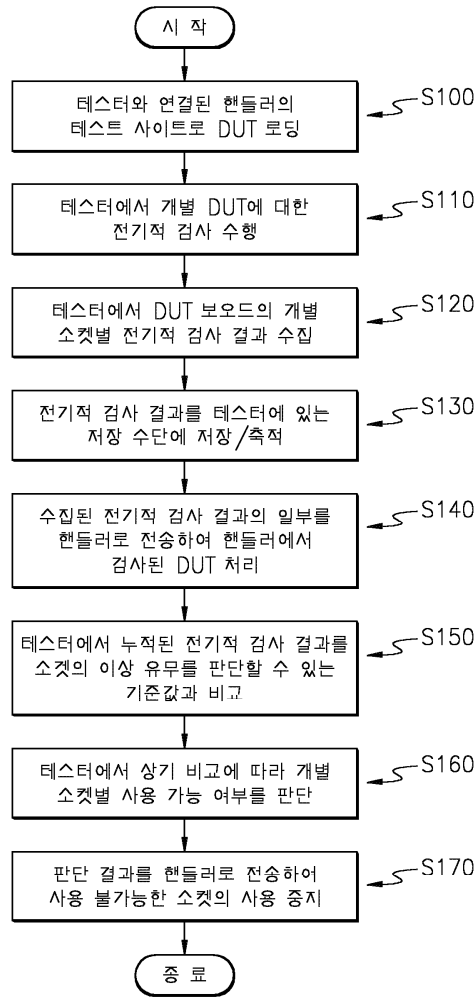
2



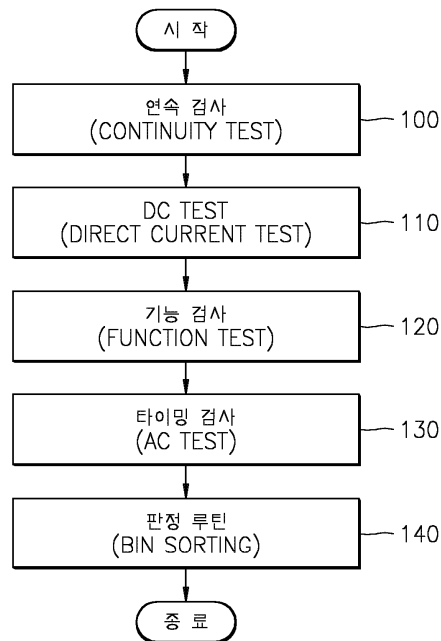
3



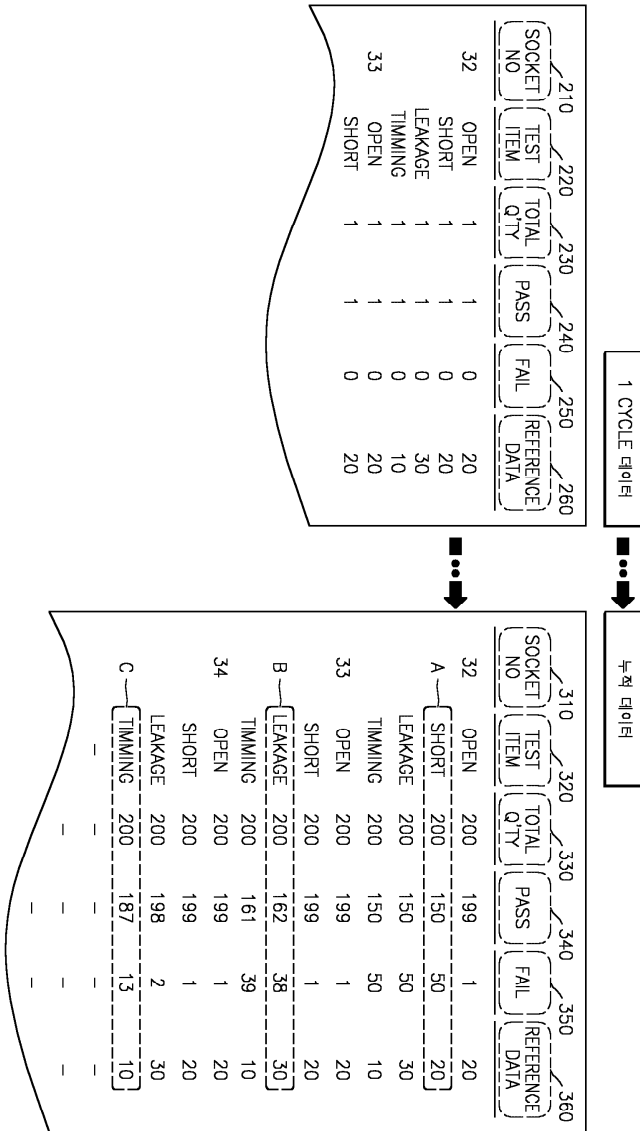
4



5



6



7

